

Notice of References Cited	Application/Control No. 10/686,705		Applicant(s)/Patent Under Reexamination SAWANAGA ET AL.	
	Examiner Tran Nguyen		Art Unit 3626	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,786,994	07-1998	Friz et al.	700/79
*	B	US-5,706,411	01-1998	McCormick et al.	358/1.14
*	C	US-6,381,557	04-2002	Babula et al.	702/183
*	D	US-6,735,549	05-2004	Ridolfo, Charles F.	702/181
*	E	US-5,874,960	02-1999	Mairs et al.	715/733
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Lie, An Algorithm for Preventive Maintenance Policy, 1986, Reliability, IEEE Transactions on, Volume: 35, Issue: 1, Page(s): 71-75
	V	Ricq, Study of CdTe and CdZnTe detectors for X-ray computed tomography, Nuclear Instruments and Methods in Physics Research Section A: Accelerators, Spectrometers, Detectors and Associated Equipment Volume 458, Issues 1-2, 1 February 2001, Pages 534-543
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.